

# RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1000M-25	Nov-95	9542 E2	OMEDATA	DD521451AEA	1.2μ NITRIDE	08 PDIP

## STRESS/JOB NO.

## READPOINT (Sample Size/No. of Fails)

Infant / High Voltage Life 125°C, 7.0 V. P-16609, P-16727	<u>48 Hr</u> 231/0	<u>336 Hr</u> 77/0	<u>1KHr</u> 77/0	<u>*Failure Rate</u> 30 Fits
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\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle -55°C to +125°C P-16728	<u>300 ~</u> 39/0	<u>1K ~</u> 39/0	<u>Cum %</u> 0.0%
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Biased Moisture 85°C/85% RH, 5.5 V. P-16729	<u>274 Hr</u> 77/0	<u>959 Hr</u> 77/0	<u>Cum %</u> 0.0%
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Autoclave 121°C/100% RH, 2 Atmos P-16730	<u>96 Hr</u> 38/0	<u>Cum %</u> 0.0%
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## Failure Mode